


<b>Search Notes</b>  	<b>Application/Control No.</b>  10798289	<b>Applicant(s)/Patent Under Reexamination</b>  HEO, HAE-JIN
	<b>Examiner</b>  TRAN, MY-CHAU T	<b>Art Unit</b>  2629

SEARCHED			
Class	Subclass	Date	Examiner
345	32, 84, 87, 88, 204, 690, 697	12/20/06	MCT
345	4, 5, 6, 32, 84, 87, 88, 204, 690, 697	12/22/06	MCT
UPDATED	UPDATED	05/09/07	MCT

SEARCH NOTES		
Search Notes	Date	Examiner
PALM Invetor; WEST - see printout	12/20/06	MCT
UPDATED - see printout	05/09/07	MCT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner